FISCHERSCOPE® X-RAY XDV®-SD

Analysis of Jewelry and Precious Metals

WINDSOR, CT (July, 2008)— For the challenges in connection with the assay determination of gold and other precious metals as well as RoHS / WEEE analysis, Fischer Technology offers X-ray fluorescence as a fast and nondestructive form of measurement. The Fischerscope® XDV®-SD, is an X-ray fluorescence spectrometer with extremely short measurement times due to the high X-Ray intensity produced by an innovative digital pulse processor. Even small electronic components or coating systems on printed circuit conductors are analyzed with pinpoint precision.

Any shape samples and precious metal coatings can be analyzed for up to 24 different elements with regard to coating thickness and element concentration which can be determined simultaneously during one measurement. Very thin coatings down into the 10-nanometer range can be measured. A high resolution color video camera generates an exact view video image of the specimen from above that is true to scale. The XDV-SD can be automated for larger random sampling due to the programmable X, Y, and Z measurement stage.

Fischer has been an innovative leader in the field of non-destructive thickness measurement and material testing instruments since 1953. Solutions are available for coating thickness measurement using the X-Ray fluorescence, beta backscatter, magnetic induction, eddy current and coulometric methods. Fischer also offers solutions for measurement of micro-hardness, conductivity, ferrite content and porosity testing.

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